

朝貴電子股份有限公司 CKM ELECTRONICS CO., LTD.

PRODUCT SPECIFICATION

CKM 2008 SERIES

WIRE TO BOARD 2.00mm PITCH CONNECTOR

INDEX

1. SCOPE	P2
2. APPLICABLE STANDARDS	P2
3. APPLICABLE SERIES	P2
4. PRODUCT SHAPE, DIMENSIONS AND MATERIALS	P2
5. ACCOMMODATED P.C. BOARD	P2
6. RATINGS	P2
7. PERFORMANCE REQUIREMENTS AND TEST DESCRIPTIONS	P3
8. TEST REQUIREMENTS AND PROCEDURES SUMMARY	P3~6
9. RECOMMENDED REFLOW TEMPERATURE PROFILE	P6
10. MATING AND UN-MATING FORCE (REMOVE LATCH)	P7
11. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE	P8

REVISION HISTORY:

REV	REVISION DESCRIPTION	DATE	CREATED/REVISED
A	INTERIM EDITION	2014/4/26	Winner Xie
В	INTERIM EDITION (With Index & Crimping Info)	2014/11/17	Jimmy Wang
С	Modify Salt spray spec	2017/5/16	Winner Xie
D	Add New Part No.	2020/10/21	Jimmy Wang

REVISION:	ECR/ECN INFORMATION:	TITLE:			SHEET No.
D	EC No.: DATE: 2020/10/21	CKM 2008 SERIES		1 of 8	
DOC	CUMENT NUMBER:	CREATED/REVISED	CHECKED BY	APPF	ROVED BY
Р	S-2008001	Jimmy Wang	Lance Cheng	Ang	jus Chen



1. SCOPE

This specification contains the test requirement of subject connectors when tested under the condition and procedure with terminals crimped on the specified maximum size wire.

2. APPLICABLE STANDARDS

EIA-364 MIL - STD – 202 / 1344 JIS C0020, C0021, C0025, C5028, C5402 UL 1977

3. 2008 SERIES

Product Name	Part No.
Housing	2008H-XX-X-HF
	2008HK-XX-X-HF
	200801XX;
Terminal	2008TXP-XXX
	200803XX;
Wafer Assembly ST.	200802XX-XX 2008WV-XX-XX-HF
	2008WVS-XX-XX-HF
	2008WS-XX-XX-HF
	2008WSS-XX-XX-HF
	2008WSS-XX-XX-HK-HF
Wafer Assembly RA.	2008WR-XX-XX-HF
	2008WM-XX-XX-HK-HF
	X. Refer to the drawing

X: Refer to the drawing

4. PRODUCT SHAPE, DIMENSIONS AND MATERIALS *See attached drawings.

5. ACCOMMODATED P.C. BOARD

- 5.1 Thickness: 0.6 mm (.024 ")~1.2mm (.047 "), 1.6 mm (.063 ")
- 5.2 P.C. Board Layout: See attached drawings

6. RATINGS

- 6.1 Current rating: 2.0A (AWG #24)
- 6.2 Voltage rating: 250V AC, DC
- 6.3 Temperature range:-62°C to +105°C
- 6.4 Applicable wire: AWG #24 to #30, Insulation O.D.: 0.90~1.60mm Max.

REVISION:	ECR/ECN INFORMATION:	<u>TITLE:</u>			SHEET No.
D	EC No.:	CKM 2008	SERIES		2 of 8
D	DATE: 2020/10/21				2018
DOC	UMENT NUMBER:	CREATED/REVISED	CHECKED BY	APP	ROVED BY
Р	S-2008001	Jimmy Wang	Lance Cheng	Ang	gus Chen



7. PERFORMANCE REQUIREMENTS AND TEST DESCRIPTIONS

The product is designed to meet the electrical, mechanical and environmental performance Requirements as specifics in 8. **REQUIREMENTS**.

8. TEST REQUIREMENTS AND PROCEDURES SUMMARY

T	TEST ITEM	REQUI	REMENT	PROCEDUI	RE	
8.1	Examination of Product		ments of product physical damage.	Per EIA-364-18 Visual inspection		
		ELEC	TRICAL REQU	IREMENT		
8.2	Contact Resistance	10mΩ Max (Initi 20mΩ Max (Fina		Dry circuit of DC 20 mV max.(JIS C5402 5.4)	max. , 1() mA
8.3	Insulation Resistance	1000MΩ Min		When applied DC 500 V adjacent terminal or grour (JIS C5402 5.2/MIL-STD 301)	nd	thod
8.4	Dielectric Withstanding Voltage	No Breakdown a	nd Flashover.	When applied AC 800 V between adjacent terminal (JIS C5402 5.2/MIL-STD 302 Cond. B)	l	
	I	MECH	IANICAL REQU	IREMENT		
	Terminal crimp Tensile strength	AWG # 24: 3.0 AWG # 26: 1.0 AWG # 28: 1. AWG # 30: 0.3	6kgf Min. 6kgf Min. 1kgf Min. 8kgf Min	Fix the crimped terminal, ap pull out force on the wire at of 25±3 mm/minute (Based C5402 6.22) *Crimping specification refe	speed rat upon JIS	e
8.6	Terminal / Housing Retention Force (For Plug)	1.5kgf Min.	Retention speed 25±3 mm per m from housing		n per min	nute
	1					
<u>/ISIO</u>		INFORMATION:	<u>TITLE:</u>			<u>SHEET</u>
D	EC No.: DATE:	2020/10/21	CKM 200	08 SERIES		3 of
	DOCUMENT NU	IMBER:	CREATED/REVISE	D CHECKED BY	APP	ROVED B
	PS-2008	001	Jimmy Wang	Lance Cheng	Δnc	jus Chen



	Mating & Un-mating force	See Item 10	Insert and withdraw connector at speed of 25 ±3 mm per minute
8.8	Durability	Contact resistance: Less than twice of initial Dielectric Withstanding Voltage: To pass Para 8.4	Connector shall be subjected to 30 cycles of insertion and withdrawal (repeatedly by the rate of 10 cycles per minute)
8.9	Pin retention force (For Header)	1.0kgf Min.	Push pin from insulator base at speed 25±3 mm per minute
8.10	Locking force	3kgf Min.	While withdrawing plug & receptacle without terminal at speed 25±3 mm per minute
		ENVIRONMENTAL RE(UIREMENTS
8.11	Temperature rise	Final Temp 105°C max.	Then carried the rated current (UL 1977)
8.12	Vibration	Appearance: No damage Discontinuity: 20mΩ Max (Final) 1 micro second max.	1.5 mm 10-55-10 HZ / minute each 2 hours for X , Y and Z directions, (MIL-STD-202,method 201A)
8.13	Heat aging	No damage Contact resistance: Less than twice of initial 20mΩ Max (Final)	105 ±2°C , 96 hours (JIS C0021/MIL-STD-202,method 108A,condition A)
8.14	Humidity	Appearance: No damage Contact resistance: 20mΩ Max (Final) Insulation resistance: To pass Para 8.3	40±2°C, 90~95% RH, 96 hours measurement must be taken within 30 min. after tested (JIS C0020/MIL-STD-202, method 103 B, condition B)

REVISION:	ECR/ECN INFORMATION:	TITLE:			SHEET No.
D	EC No.:	CKM 2008	SERIES		4 of 8
U	DATE: 2020/10/21		01		4010
DOC	CUMENT NUMBER:	CREATED/REVISED	CHECKED BY	APP	ROVED BY
Р	S-2008001	Jimmy Wang	Lance Cheng	Ang	gus Chen



8.15	Temperature cycling	Appearance: No damage Contact resistance: 20mΩ Max (Final)	5 cycles consists of :(JIS C0025) (1)-40°C+0/-03°C,~ 30 min. (2) 25°C, ~ 3 min. (3) 105°C+3/-0°C, ~30 min. (4) 25°C, ~ 3 min.
8.16	Salt spray	Appearance: No damage Contact resistance: 20mΩ Max (Final)	Temperature: 35±2°C Solution: 5±1% Spray time: Contact PRE- Bright TIN Plated 12±4Hours Spray time: Contact Post-Bright tin Plated 24±4Hours Measurement must be taken after water rinse(JIS C5402 7.1/MIL-STD-202, method 101 D, condition B)
8.17	Solder ability	Minimum: 95% of immersed area	Lead-Free Process for DIP Type: Soldering time: 3±0.5 second Soldering pot: 245±5°C
8.18	Resistance to Reflow heat (SMT)	No damage	Refer Reflow temperature profile Profile refer to Figure 2
8.19	Resistance to soldering heat	No damage	Apply solder iron in solder tail Temperature: 380±5℃, ±5 sec.

REVISION:	ECR/ECN INFORMATION:	<u>TITLE:</u>			SHEET No.
D	EC No.: DATE: 2020/10/21	CKM 2008 SERIES		5 of 8	
DOC	UMENT NUMBER:	CREATED/REVISED	CHECKED BY	APP	ROVED BY
Р	S-2008001	Jimmy Wang	Lance Cheng	Ang	gus Chen



朝貴電子股份有限公司

CKM ELECTRONICS CO., LTD.

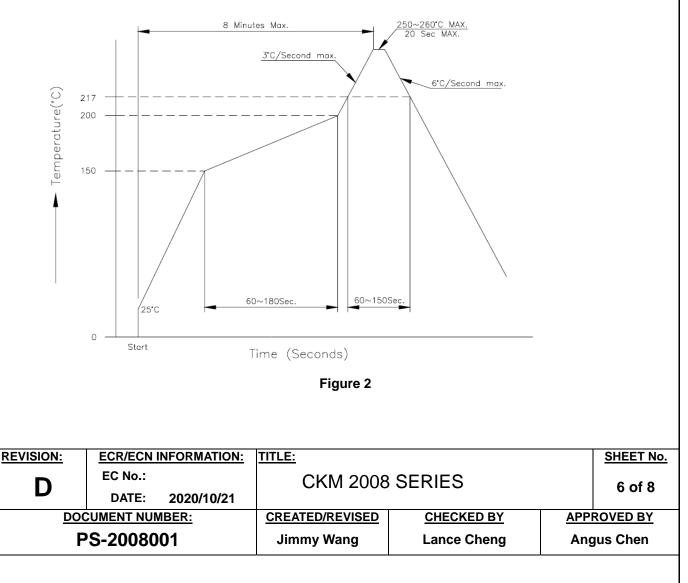
8.20 Crimping specification:

2008T0X-XXX					
Wire Size(AWG)		#24	#26	#28	#30
	CRIMP WIDTH	1.3±0.1			
1. CONDUCTOR (mm)	CRIMP HEIGHT	0.85~0.76	0.75~0.65	0.65~0.54	0.54~0.45
	CRIMP WIDTH	1.50~1.55			
2. INSULATION (mm)	CRIMP HEIGHT	1.75	1.60	1.45	1.29
CRIMP STRENGTH		3.0Kgf	1.8Kgf	1.1Kgf	0.8Kgf
		(MIN)	(MIN)	(MIN)	(MIN)

Figure 1

9. Recommended Reflow Temperature Profile:

Using Lead-Free Solder Paste



朝貴電子股份有限公司 CKM ELECTRONICS CO., LTD.

10. Mating and Un-mating Force (Remove Latch):

KI

[2008T0X-XX]

PIN No.	At	Initial	At 30th
PIIN INO.	Mating (kgf Max.)	Un-mating (kgf Min.)	Un-mating (kgf Min.)
6	2.30	1.50	1.20
8	2.90	1.75	1.35
10	3.50	2.00	1.50
12	4.10	2.25	1.65
14	4.70	2.50	1.80
16	5.30	2.75	1.95
18	5.90	3.00	2.10
20	6.50	3.25	2.25
22	7.10	3.50	2.40
24	7.70	3.75	2.55
26	8.30	4.00	2.70
28	8.90	4.25	2.85
30	9.50	4.50	3.00
32	10.10	4.75	3.15
34	10.70	5.00	3.30

[2008T0X-XXL]

PIN No.	At Initial		At 30th	
	Mating (kgf Max.)	Un-mating (kgf Min.)	Un-mating (kgf Min.)	
20	4.2	2.0	1.4	
22	4.6	2.2	1.6	
24	5.0	2.4	1.8	
26	5.4	2.6	2.0	
28	5.8	2.8	2.2	
30	6.2	3.0	2.4	
32	6.4	3.2	2.6	
34	6.8	3.4	2.8	
36	7.2	3.6	3.0	
38	7.6	3.8	3.2	
40	8.0	4.0	3.4	

ECR/ECN INFORMATION: **REVISION:**

TITLE:

SHEET No.

D	EC No.: DATE:	2020/10/21	CKM 2008 SERIES			7 of 8
DOCUMENT NUMBER:			CREATED/REVISED	CHECKED BY	APPROVED BY	
PS-2008001			Jimmy Wang	Lance Cheng	Angus Chen	



朝貴電子股份有限公司

CKM ELECTRONICS CO., LTD.

11. PRODUCT QUALIFICATION AND REQUALIFICATION TEST SEQUENCE **Test Group** С F Ι Test or Examination А В D Е G Н J Κ Test Sequence (a) Examination of Product 1.8 1.7 1 1 1.3 1 1.5 1.5 1.3 1.3 1.5 Contact Resistance 2,7 2.6 2,4 2,4 2,4 Insulation Resitance 3,5 Dielectric withstanding 3,6 Voltage Terminal crimp Tensile 2 strength Terminal / Housing Insertion Force 2 (For Plug) Mating & Un-mating 4 force 5 Durability **Temperature Rise** 2 Vibration 2 3 Heat aging 4 Humidity Temperature cycling 3 Salt spray 3 Solder ability 2 Resistance to Reflow 2 heat (SMT) 5 5 5 Sample Size 5 5 5 5 5 5 5 5 **REVISION: ECR/ECN INFORMATION:** TITLE: SHEET No. EC No.: CKM 2008 SERIES D 8 of 8 DATE: 2020/10/21 DOCUMENT NUMBER: CREATED/REVISED APPROVED BY CHECKED BY **PS-2008001** Jimmy Wang Lance Cheng Angus Chen